ezAFM™

Atomic Force Microscope for Research, Education and QC Applications

• Innovative technology with superior performance
• Setup under an hour
• Compact
• Portable
**Technical Specification**

- Alignment free cantilevers, commercially available
- 120x120x40μm or 40x40x4μm scan range
- Contact, Dynamic/Phase Imaging, Lateral Force & MFM modes
- 65fm/√Hz noise floor
- 2μm resolution integrated optical microscope
- 8MP, 390x230μm FOV, 3264x2448 pixels, 30fps, video camera
- 24 Bit ADCs/DACs
- Digital Feedback with FPGA/DSP
- Sample Size, 10x10x5mm (Configurable or unlimited sample size)
- USB interface
- Unlimited user license
- Free software upgrades for lifetime
- Side view camera

**Extended Imaging Options**

- Scratching Lithography
- Scanning Tunneling Microscopy (ezSTM)
- Liquid Cell

**Accessories**

- Signal Access Module
- 40mm stroke XY motorized sample positioner
- 2mm stroke XY manual sample positioner

*Every system will include one of the standard imaging modes. Further modes can be added optionally.*